

Stephane Grauby

List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/2956398/publications.pdf>

Version: 2024-02-01

59
papers

1,049
citations

471061

17
h-index

433756

31
g-index

60
all docs

60
docs citations

60
times ranked

1023
citing authors

| # | ARTICLE | IF | CITATIONS |
|----|--|------|-----------|
| 1 | High resolution photothermal imaging of high frequency phenomena using a visible charge coupled device camera associated with a multichannel lock-in scheme. Review of Scientific Instruments, 1999, 70, 3603-3608. | 0.6 | 128 |
| 2 | Scanning thermal microscopy of individual silicon nanowires. Journal of Applied Physics, 2011, 109, . | 1.1 | 78 |
| 3 | Thermal exchange radius measurement: Application to nanowire thermal imaging. Review of Scientific Instruments, 2010, 81, 073701. | 0.6 | 63 |
| 4 | Decrease in thermal conductivity in polymeric P3HT nanowires by size-reduction induced by crystal orientation: new approaches towards thermal transport engineering of organic materials. Nanoscale, 2014, 6, 7858-7865. | 2.8 | 63 |
| 5 | Calibration procedure for temperature measurements by thermoreflectance under high magnification conditions. Applied Physics Letters, 2004, 84, 822-824. | 1.5 | 62 |
| 6 | Coherent phonons in Si ¹⁰⁰ /SiGe superlattices. Physical Review B, 2007, 75, . | 1.1 | 58 |
| 7 | Fabrication of Bi ₂ Te ₃ nanowire arrays and thermal conductivity measurement by 3D-scanning thermal microscopy. Journal of Applied Physics, 2013, 113, . | 1.1 | 56 |
| 8 | Heterodyne picosecond thermoreflectance applied to nanoscale thermal metrology. Journal of Applied Physics, 2011, 110, . | 1.1 | 48 |
| 9 | Four different approaches for the measurement of IC surface temperature: application to thermal testing. Microelectronics Journal, 2002, 33, 689-696. | 1.1 | 41 |
| 10 | Nanoscale Block Copolymer Ordering Induced by Visible Interferometric Micropatterning: A Route towards Large Scale Block Copolymer 2D Crystals. Advanced Materials, 2013, 25, 213-217. | 11.1 | 40 |
| 11 | Si and SiGe Nanowires: Fabrication Process and Thermal Conductivity Measurement by 3D-Scanning Thermal Microscopy. Journal of Physical Chemistry C, 2013, 117, 9025-9034. | 1.5 | 33 |
| 12 | Strategies for built-in characterization testing and performance monitoring of analog RF circuits with temperature measurements. Measurement Science and Technology, 2010, 21, 075104. | 1.4 | 26 |
| 13 | Thermoreflectance calibration procedure on a laser diode: application to catastrophic optical facet damage analysis. IEEE Electron Device Letters, 2005, 26, 461-463. | 2.2 | 24 |
| 14 | Imaging setup for temperature, topography, and surface displacement measurements of microelectronic devices. Review of Scientific Instruments, 2003, 74, 645-647. | 0.6 | 23 |
| 15 | Characterization of the thermal behavior of PN thermoelectric couples by scanning thermal microscope. Microelectronics Journal, 2004, 35, 797-803. | 1.1 | 21 |
| 16 | Thermal parameters identification of micrometric layers of microelectronic devices by thermoreflectance microscopy. Microelectronics Journal, 2004, 35, 811-816. | 1.1 | 20 |
| 17 | Cross-plan Si ¹⁰⁰ /SiGe superlattice acoustic and thermal properties measurement by picosecond ultrasonics. Journal of Applied Physics, 2007, 101, 013705. | 1.1 | 20 |
| 18 | Study of thermomechanical properties of Si ¹⁰⁰ /SiGe superlattices using femtosecond transient thermoreflectance technique. Applied Physics Letters, 2005, 87, 103506. | 1.5 | 16 |

| # | ARTICLE | IF | CITATIONS |
|----|---|-----|-----------|
| 19 | A heterodyne method for the thermal observation of the electrical behavior of high-frequency integrated circuits. Measurement Science and Technology, 2008, 19, 115704. | 1.4 | 16 |
| 20 | Temperature variation mapping of a microelectromechanical system by thermoreflectance imaging. IEEE Electron Device Letters, 2005, 26, 78-80. | 2.2 | 15 |
| 21 | Laser scanning thermoreflectance imaging system using galvanometric mirrors for temperature measurements of microelectronic devices. Review of Scientific Instruments, 2007, 78, 074902. | 0.6 | 15 |
| 22 | Dynamical behavior and cut-off frequency of Si/SiGe microcoolers. Superlattices and Microstructures, 2007, 41, 7-16. | 1.4 | 15 |
| 23 | Comparison of thermoreflectance and scanning thermal microscopy for microelectronic device temperature variation imaging: Calibration and resolution issues. Microelectronics Reliability, 2008, 48, 204-211. | 0.9 | 15 |
| 24 | Surface displacement imaging by interferometry with a light emitting diode. Applied Optics, 2002, 41, 4996. | 2.1 | 14 |
| 25 | Laser diode COFD analysis by thermoreflectance microscopy. Microelectronics Reliability, 2001, 41, 1597-1601. | 0.9 | 13 |
| 26 | High resolution AC temperature field imaging. Electronics Letters, 1997, 33, 1688. | 0.5 | 13 |
| 27 | Dynamical behavior of the scanning thermal microscope (SThM) thermal resistive probe studied using Si/SiGe microcoolers. Superlattices and Microstructures, 2005, 38, 69-75. | 1.4 | 10 |
| 28 | Time gating imaging through thick silicon substrate: a new step towards backside characterisation. Microelectronics Reliability, 2006, 46, 1520-1524. | 0.9 | 10 |
| 29 | Joule expansion imaging techniques on microelectronic devices. Microelectronics Journal, 2009, 40, 1367-1372. | 1.1 | 10 |
| 30 | Precise Facet Temperature Distribution of High- Power Laser Diodes: Unpumped Window Effect. IEEE Photonics Technology Letters, 2015, 27, 1002-1005. | 1.3 | 10 |
| 31 | Laser Seebeck Effect Imaging (SEI) and Peltier Effect Imaging (PEI): complementary investigation methods.. Microelectronics Reliability, 2003, 43, 1609-1613. | 0.9 | 8 |
| 32 | Applications of temperature phase measurements to IC testing. Microelectronics Reliability, 2004, 44, 95-103. | 0.9 | 7 |
| 33 | Ultimate-resolution thermal spectroscopy in time domain thermoreflectance (TDTR). Journal of Applied Physics, 2020, 128, 065106. | 1.1 | 7 |
| 34 | Si and Ge allotrope heterostructured nanowires: experimental evaluation of the thermal conductivity reduction. Nanotechnology, 2019, 30, 375704. | 1.3 | 5 |
| 35 | Harmonic Regime Analysis and Inverse Method Applied to The Simultaneous Determination of Thermoelectric Properties. , 2006, , . | | 4 |
| 36 | Determination of ZT of PN thermoelectric couples by AC electrical measurement. , 0, , . | | 3 |

| # | ARTICLE | IF | CITATIONS |
|----|---|-----|-----------|
| 37 | Heterodyne lock-in thermal coupling measurements in integrated circuits: Applications to test and characterization. Review of Scientific Instruments, 2009, 80, 026101. | 0.6 | 3 |
| 38 | Nanoscale Thermal Transport Studied With Heterodyne Picosecond Thermoreflectance. , 2009, , . | | 3 |
| 39 | Electro-thermal characterization of a differential temperature sensor in a 65nm CMOS IC: Applications to gain monitoring in RF amplifiers. Microelectronics Journal, 2014, 45, 484-490. | 1.1 | 3 |
| 40 | Measurement of thermally induced vibrations of microelectronic devices by use of a heterodyne electronic speckle pattern interferometry imaging technique. Applied Optics, 2003, 42, 1763. | 2.1 | 2 |
| 41 | Thermal study of PN thermoelectric couple by laser induced Seebeck EMF measurement. Superlattices and Microstructures, 2004, 35, 375-387. | 1.4 | 2 |
| 42 | ElectroStatic Discharge Fault Localization by Laser Probing. Microelectronics Reliability, 2005, 45, 1482-1486. | 0.9 | 2 |
| 43 | Characterization of thermoelectric devices by laser induced Seebeck electromotive force (LIS-EMF) measurement. Journal Physics D: Applied Physics, 2005, 38, 1489-1497. | 1.3 | 2 |
| 44 | Using Temperature as Observable of the Frequency Response of RF CMOS Amplifiers. , 2008, , . | | 2 |
| 45 | Effect of nanostructuration on the thermal conductivity of thermoelectric materials. , 2013, , . | | 2 |
| 46 | Investigations on electro-optical and thermal performances degradation of high power density GaAs-based laser diode in vacuum environment. Microelectronics Reliability, 2015, 55, 1746-1749. | 0.9 | 2 |
| 47 | Thermal Behavior of High Power GaAs-Based Laser Diodes in Vacuum Environment. IEEE Photonics Technology Letters, 2016, 28, 665-668. | 1.3 | 2 |
| 48 | Imaging Thermoelectric Properties at the Nanoscale. Nanomaterials, 2021, 11, 1199. | 1.9 | 2 |
| 49 | 2 MHz modulated photothermal imaging using a CCD camera coupled to a multichannel lock-in detection. , 1999, , . | | 1 |
| 50 | Study of the thermal behaviour of PN thermoelectric couples by laser probe interferometric measurement. , 0, , . | | 1 |
| 51 | Application of Picosecond Ultrasonics to Non-Destructive Analysis in VLSI circuits. Microelectronics Reliability, 2003, 43, 1803-1807. | 0.9 | 1 |
| 52 | Thermal and thermomechanical study of micro-refrigerators on a chip based on semiconductor heterostructures. , 0, , . | | 1 |
| 53 | Simulation of Si/SiGe micro-cooler by thermal quadrupoles method. , 2005, , . | | 1 |
| 54 | Joule expansion imaging techniques on microelectronic devices. , 2007, , . | | 1 |

| # | ARTICLE | IF | CITATIONS |
|----|---|-----|-----------|
| 55 | Laser scanning thermomechanical imaging of microelectronic devices. , 2008, , . | | 1 |
| 56 | Fast Laser Scanning Imaging System for Surface Displacement Measurements. IEEE Electron Device Letters, 2009, 30, 222-224. | 2.2 | 1 |
| 57 | Strain Energy Imaging of a Power MOS Transistor Using Speckle Interferometry. IEEE Transactions on Reliability, 2004, 53, 293-296. | 3.5 | 0 |
| 58 | Investigating Coherent Zone-Folded Acoustic Phonons in Si/SiGe Superlattices by Transient Thermoreflectance Technique. Materials Research Society Symposia Proceedings, 2009, 1221, 8031. | 0.1 | 0 |
| 59 | Nonlinearity characterization of temperature sensing systems for integrated circuit testing by intermodulation products monitoring. Review of Scientific Instruments, 2011, 82, 094902. | 0.6 | 0 |